Search Notes



Application/Control No.		Applicant(s)/Patent under Reexamination	
10/716,45	2	LEE ET AL.	
Examiner		Art Unit	
John L. Go	oodrow	1756	

SEARCHED					
Class	Subclass	Date	Examiner		
430	59.4	2/20/06	JG		
	59.1				
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399	116				
	159				

INTERFERENCE SEARCHED					
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